

Error Analysis

Monte Carlo Technique

02 October 2013

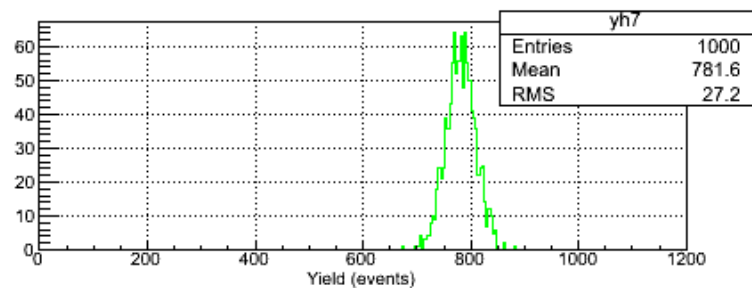
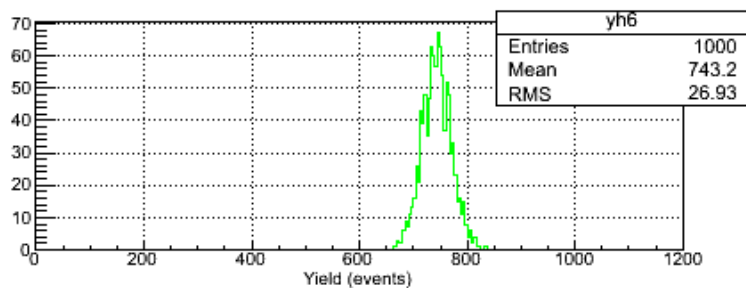
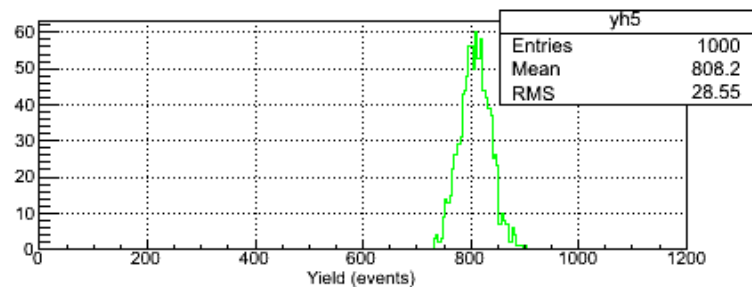
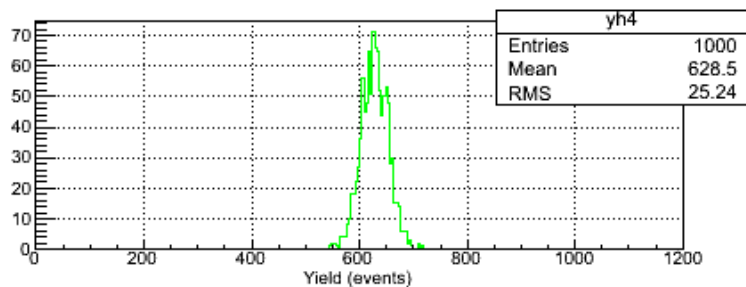
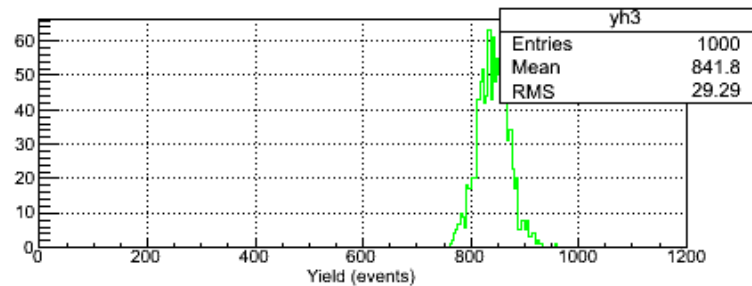
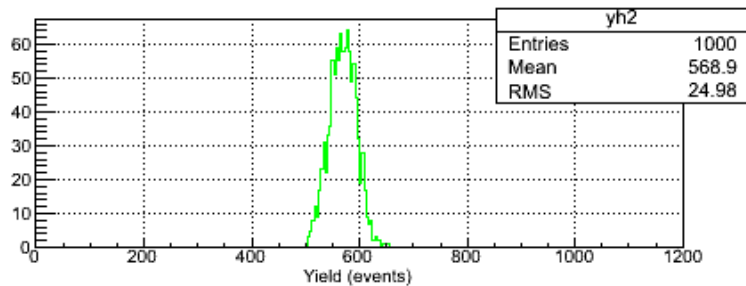
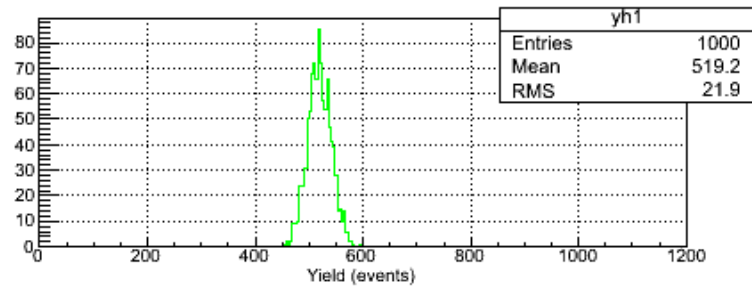
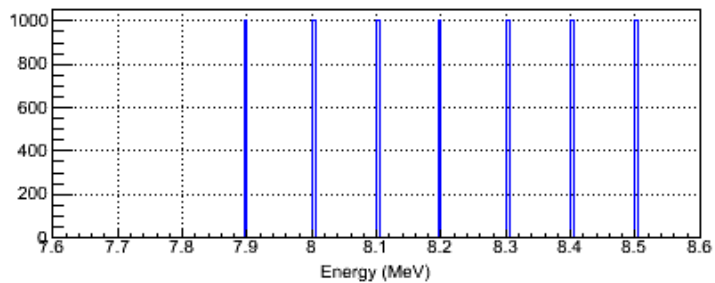
Statistical Errors

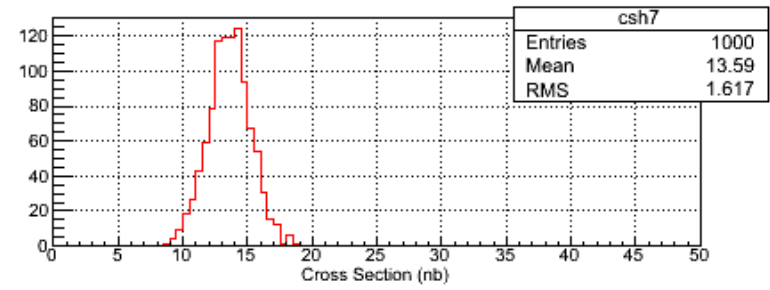
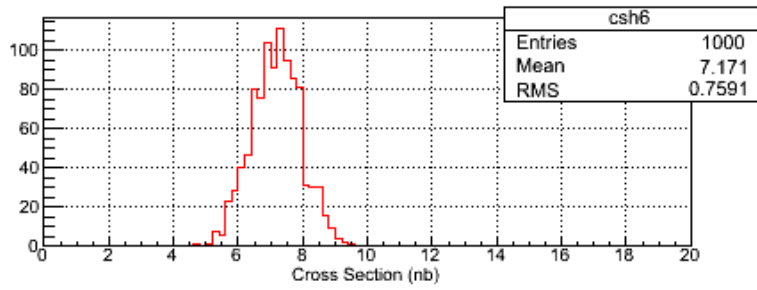
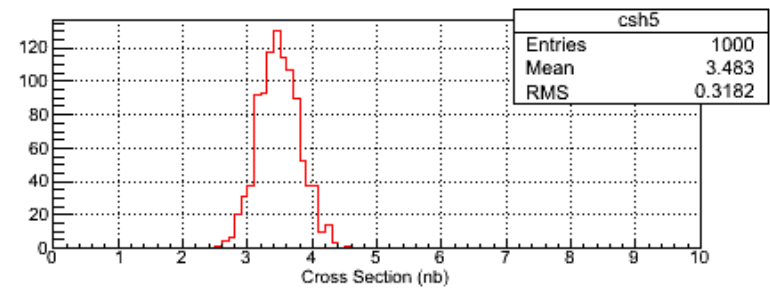
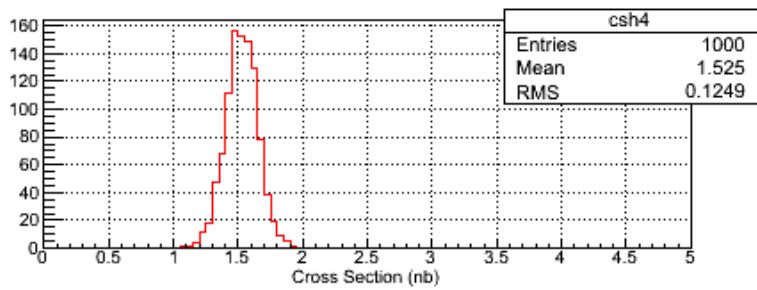
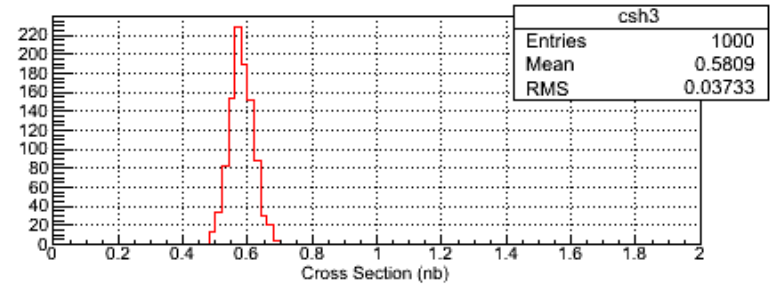
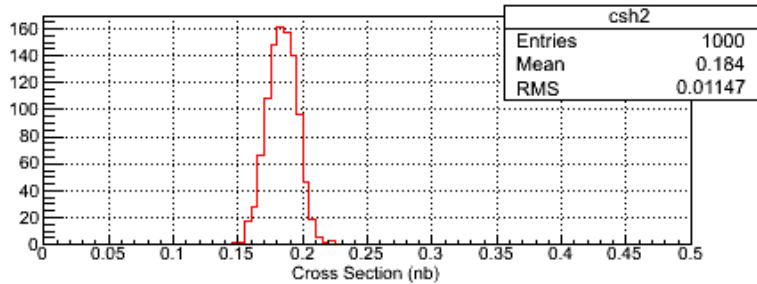
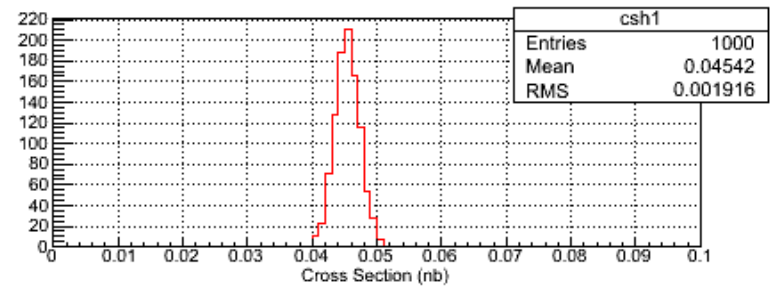
Statistical Error – No Background

- I. Calculate the yield
- II. Allow for statistical fluctuations:

$$y_i = \text{gRandom} \rightarrow \text{Gaus}(y_i, \text{Sqrt}(y_i))$$

- III. Unfold cross section
- IV. Repeat for 1000 tries





Electron Beam K. E.	Beam Current (μA)	Time (hour)	y_i	dy_i (no bg)	dy_i/y_i (no bg, %)
7.9	100	100	519	22	4.2
8.0	100	20	569	25	4.4
8.1	80	10	842	29	3.5
8.2	20	10	629	25	4.0
8.3	10	10	808	29	3.5
8.4	4	10	743	27	3.6
8.5	2	10	782	27	3.5

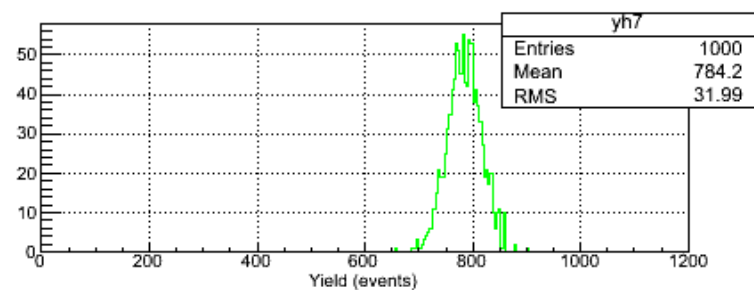
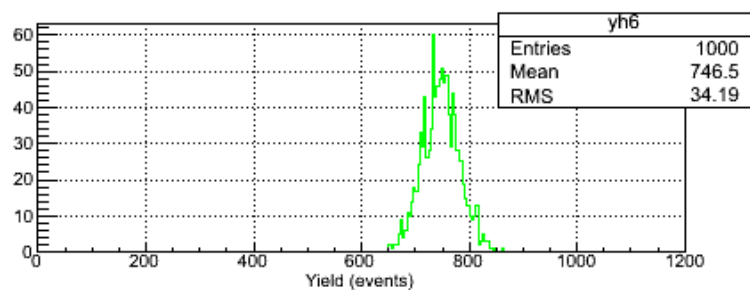
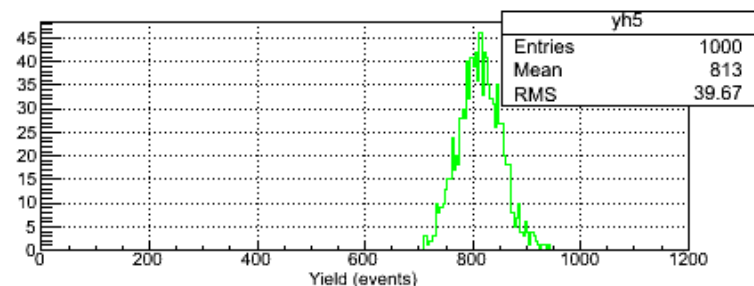
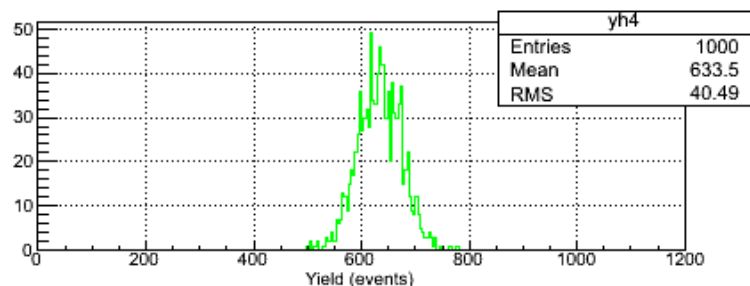
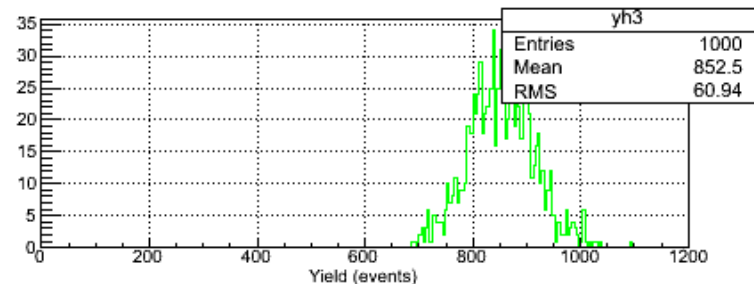
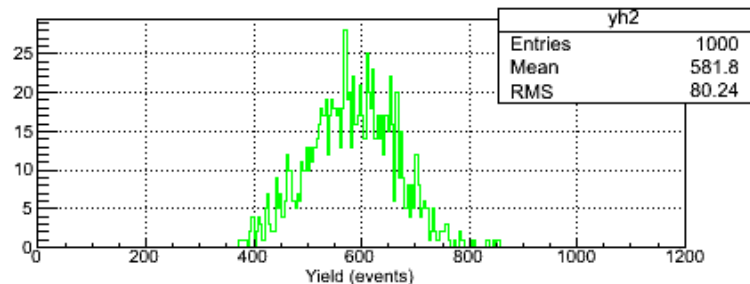
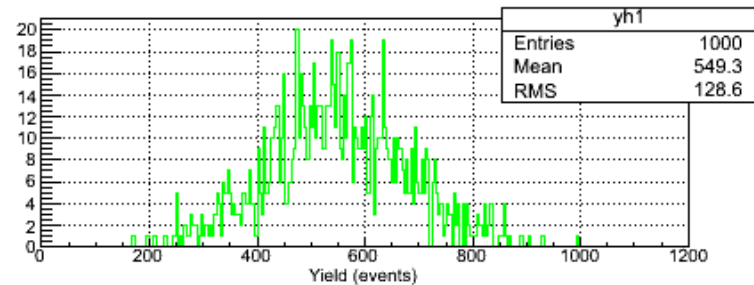
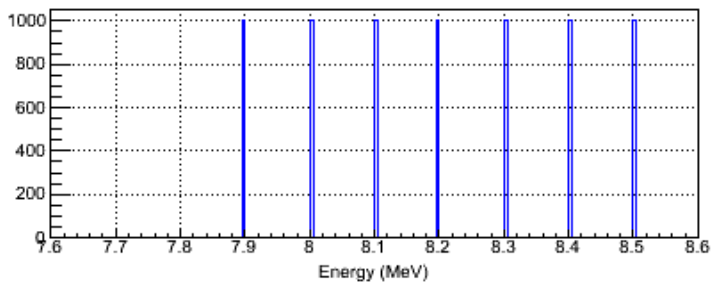
Electron Beam K. E.	Cross Section (nb)	Stat Error (no bg, %)
7.9	0.045	4.2
8.0	0.184	6.2
8.1	0.58	6.4
8.2	1.53	8.2
8.3	3.48	9.1
8.4	7.2	10.6
8.5	13.6	11.9

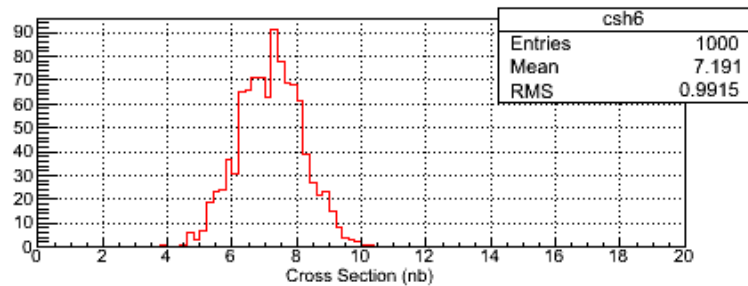
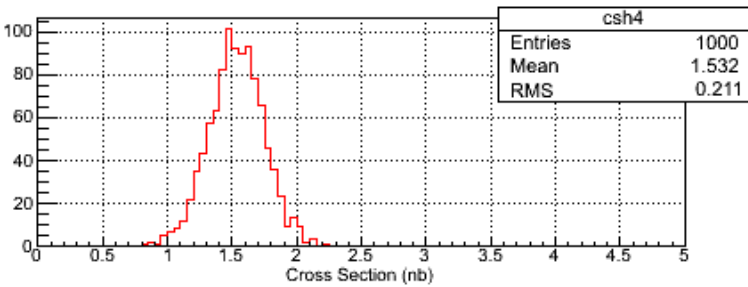
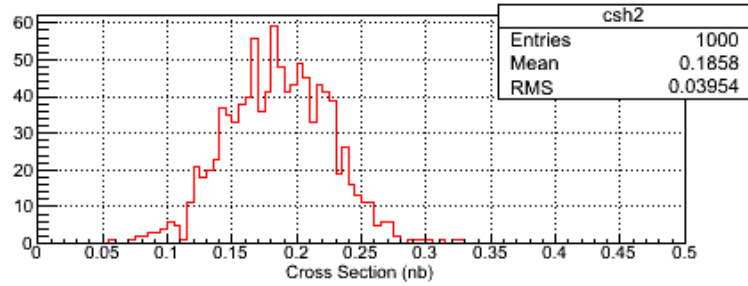
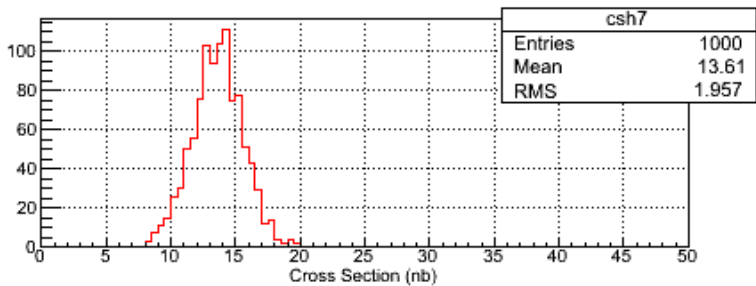
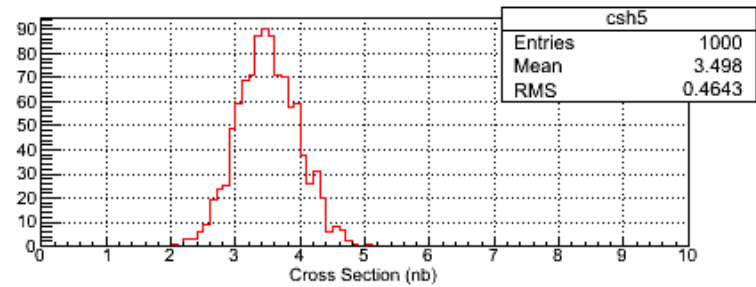
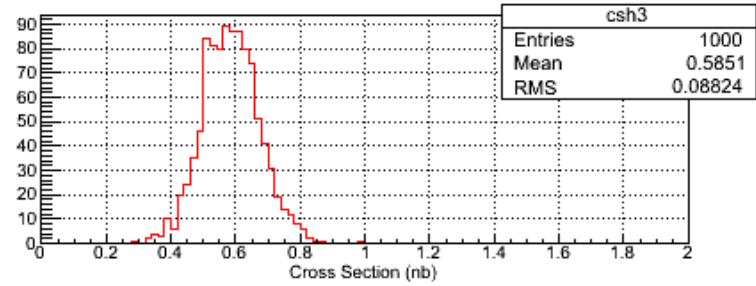
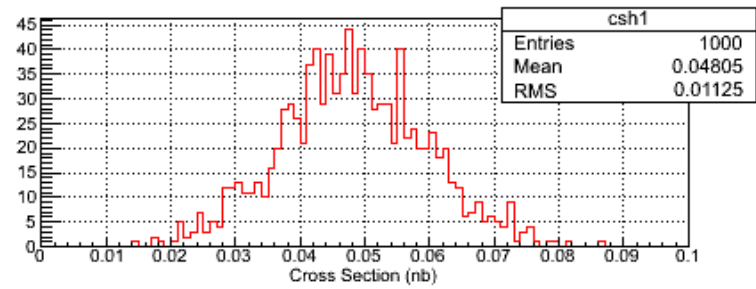
Statistical Error – With Background

- I. Calculate the yield
- II. Calculate the background yield from ^{18}O
- III. Allow for statistical fluctuations:

$$y_i = \text{gRandom} \rightarrow \text{Gaus}(y_i, \text{Sqrt}(y_i + 2y_i^{bg}))$$

- IV. Unfold cross section
- V. Repeat for 1000 tries





Electron Beam K. E.	Beam Current (μA)	Time (hour)	y_i	dy_i (with bg)	dy_i/y_i (with bg, %)
7.9	100	100	549	129	23.4
8.0	100	20	582	80	13.8
8.1	80	10	852	61	7.1
8.2	20	10	633	40	6.4
8.3	10	10	813	40	4.9
8.4	4	10	747	34	4.6
8.5	2	10	784	32	4.1

Electron Beam K. E.	Cross Section (nb)	Stat Error (with bg, %)
7.9	0.048	23.4
8.0	0.186	21.3
8.1	0.59	15.1
8.2	1.53	13.8
8.3	3.50	13.3
8.4	7.2	13.8
8.5	13.6	14.4

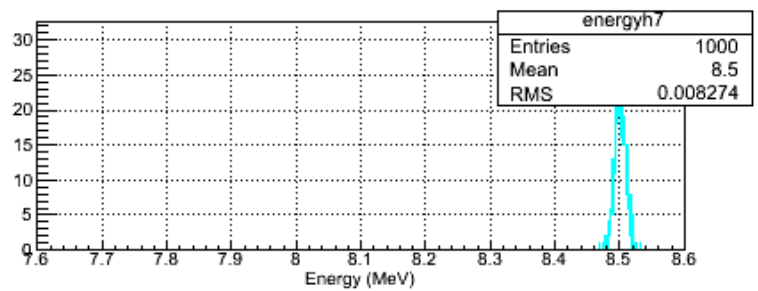
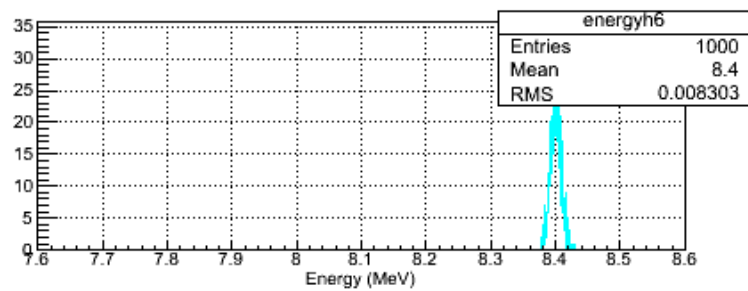
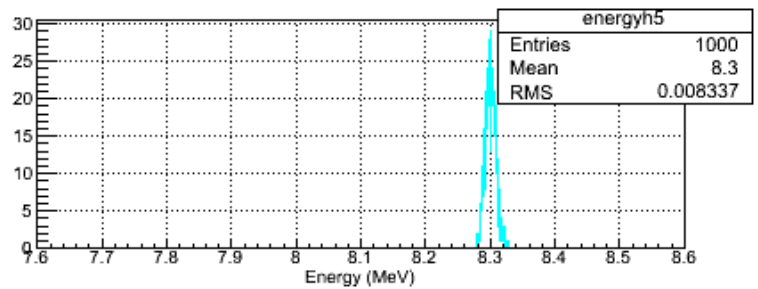
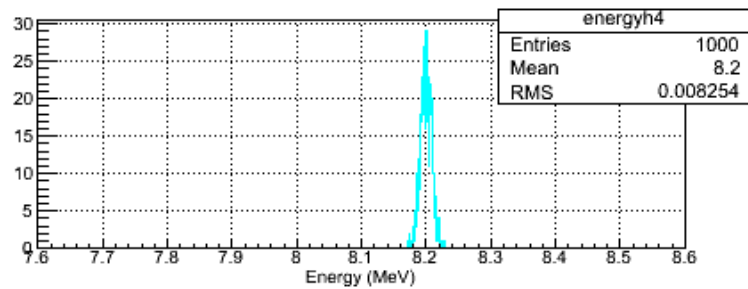
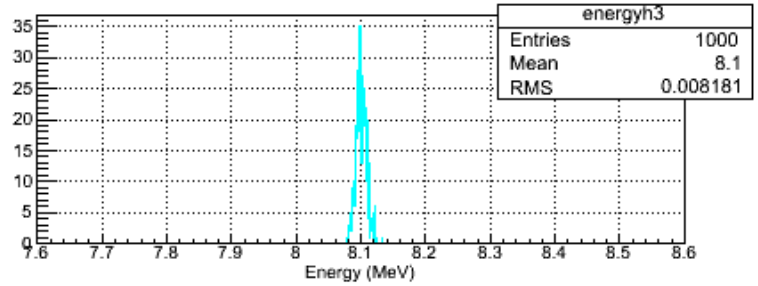
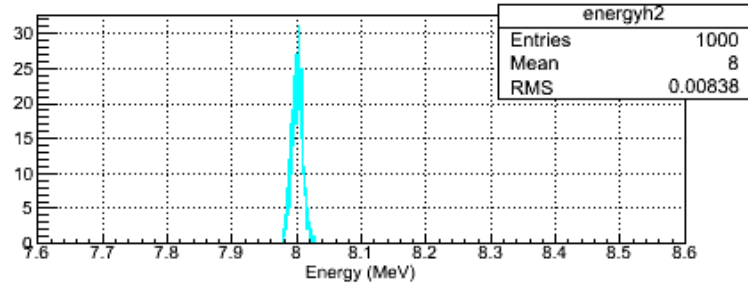
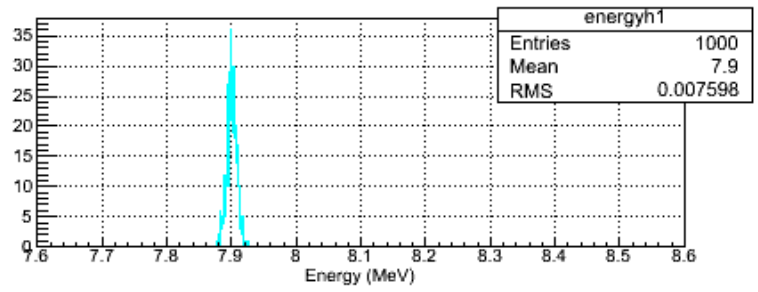
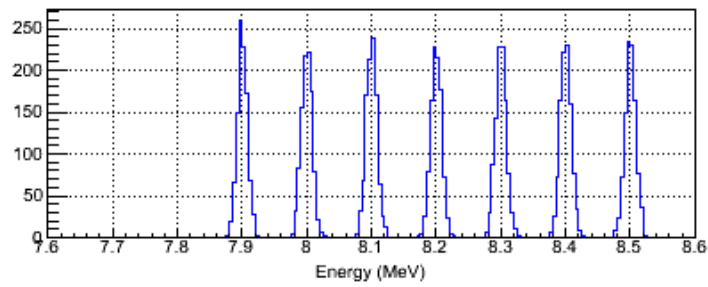
Absolute Systematic Errors

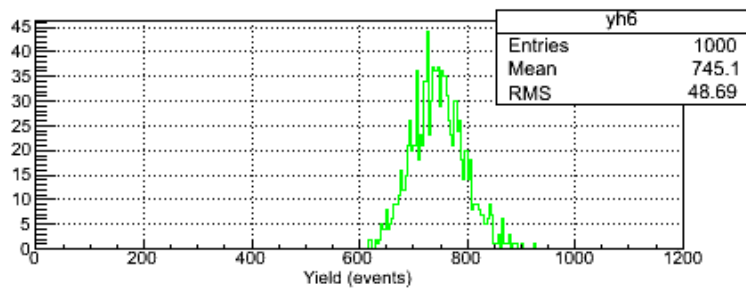
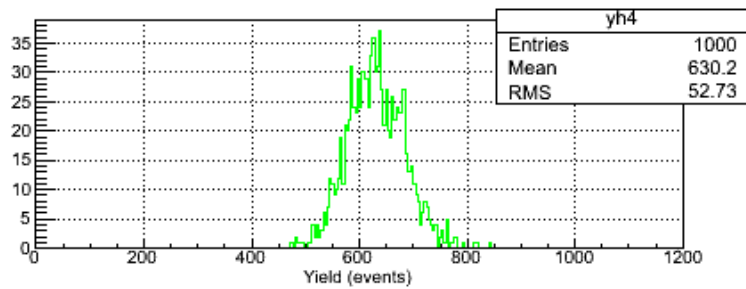
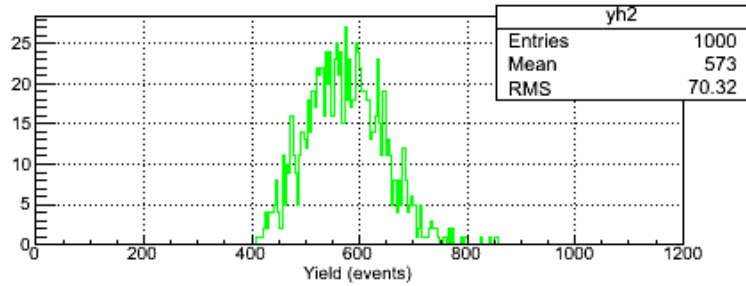
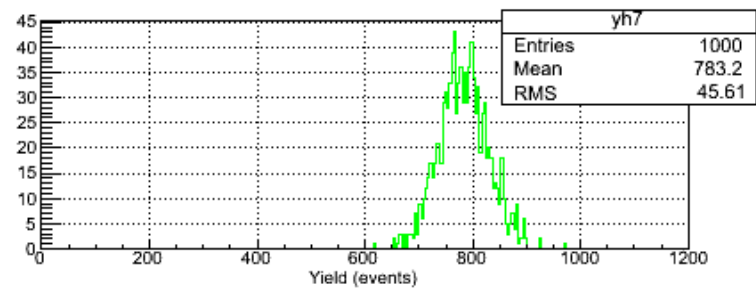
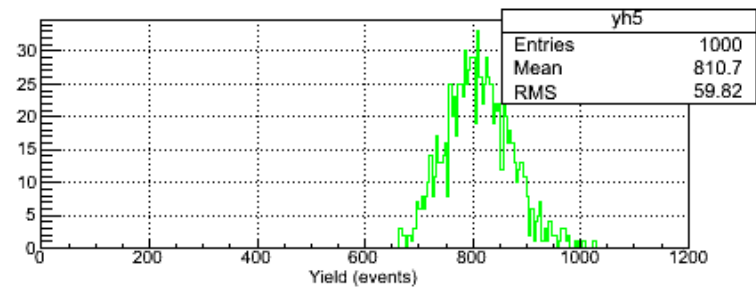
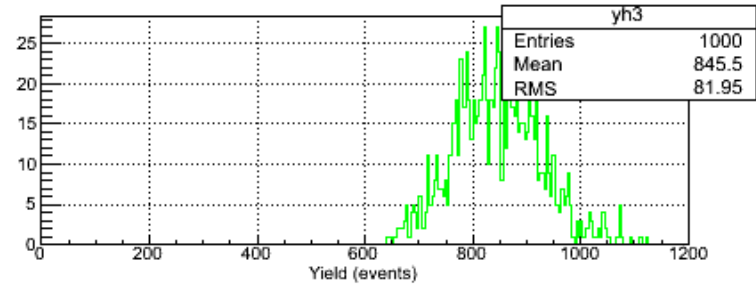
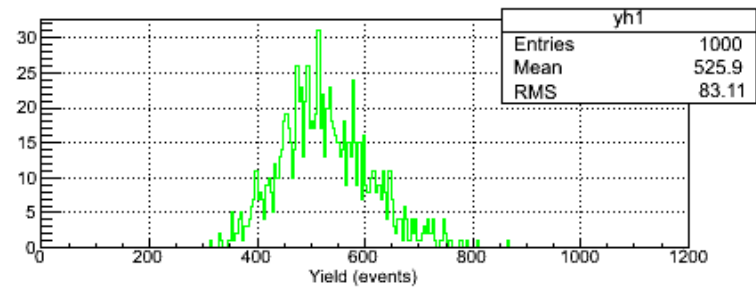
Absolute Beam Energy

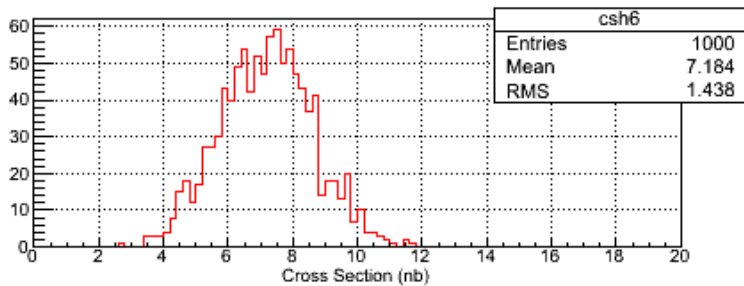
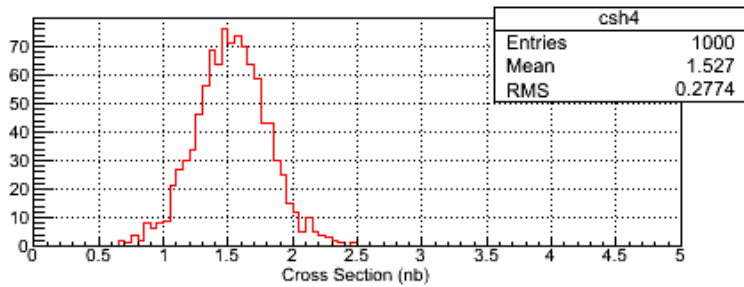
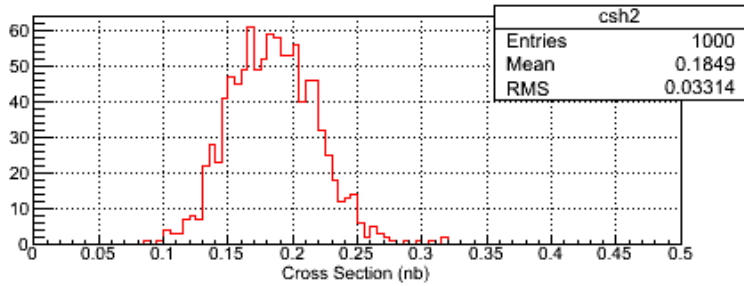
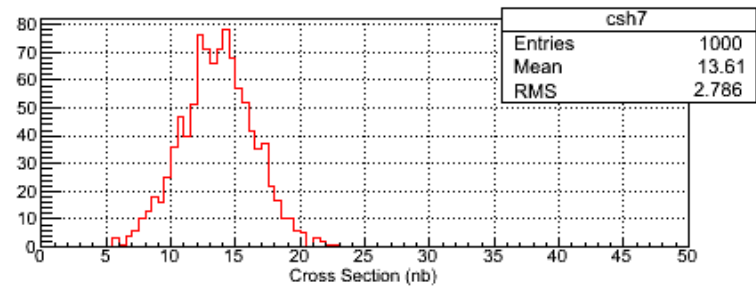
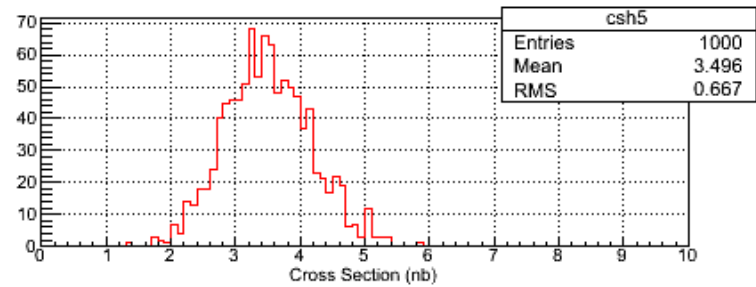
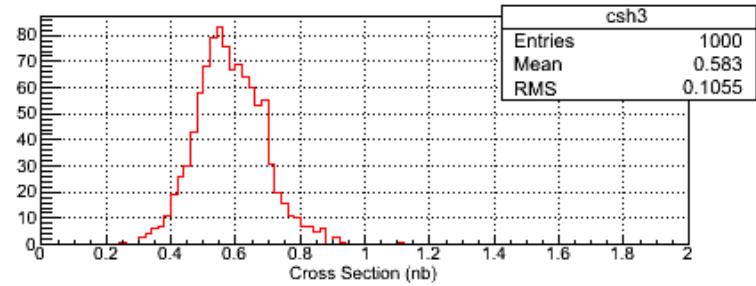
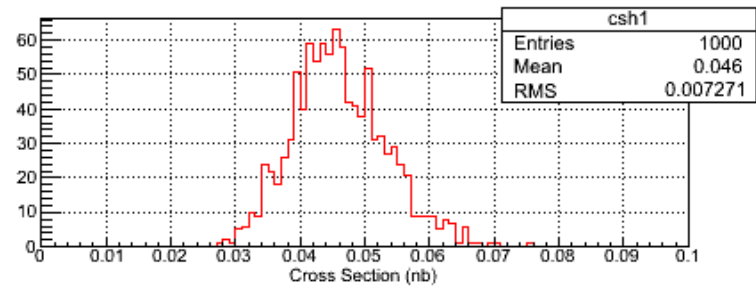
- I. Calculate the N_{ij} for each nominal beam energy, E_i (since we will use GEANT4)
- II. Allow for absolute beam energy to change by:

$$E_i = E_i * gRandom \rightarrow Gaus(1, 0.001)$$

- III. Calculate the yield
- IV. Unfold cross section
- V. Repeat for 1000 tries







Electron Beam K. E.	Beam Current (μA)	Time (hour)	y_i	dy_i/y_i (%)
7.9	100	100	526	15.8
8.0	100	20	573	12.3
8.1	80	10	846	9.7
8.2	20	10	630	8.4
8.3	10	10	811	7.4
8.4	4	10	745	6.5
8.5	2	10	783	5.8

Electron Beam K. E.	Cross Section (nb)	Sys Error (Energy, %)
7.9	0.046	15.8
8.0	0.185	17.9
8.1	0.58	18.1
8.2	1.53	18.2
8.3	3.50	19.1
8.4	7.2	20.0
8.5	13.6	20.5

Other Absolute Systematic Errors

- I. Calculate the N_{ij} for each nominal beam energy, E_i (since we will use GEANT4)
- II. Allow for absolute beam energy to change by:

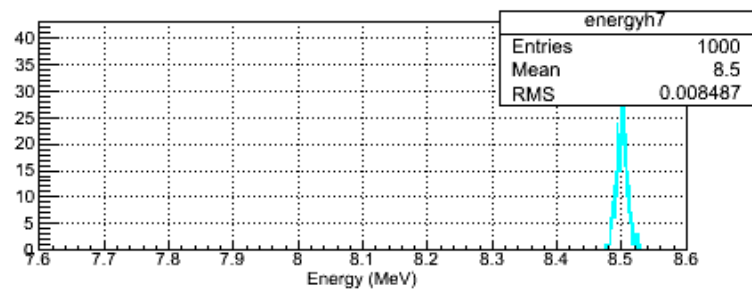
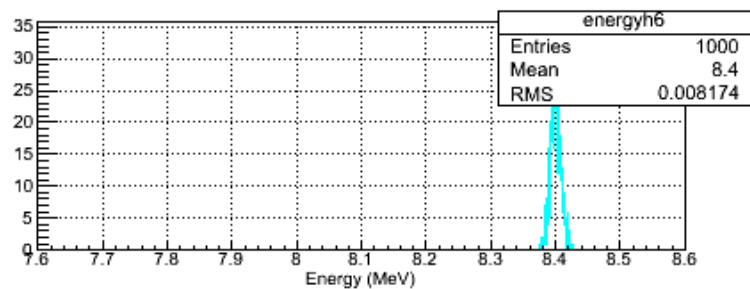
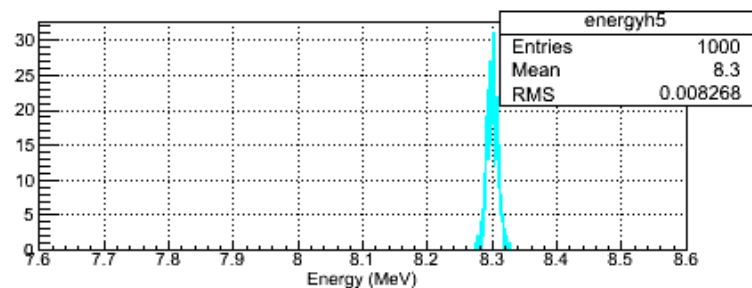
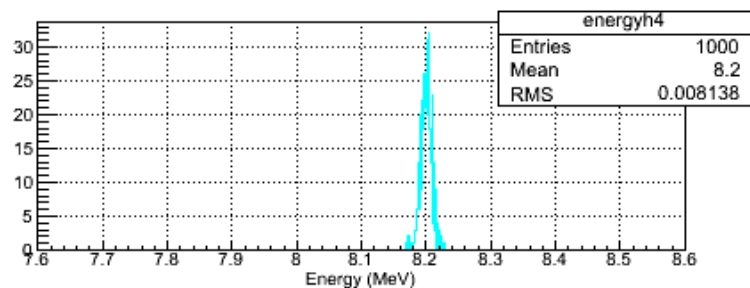
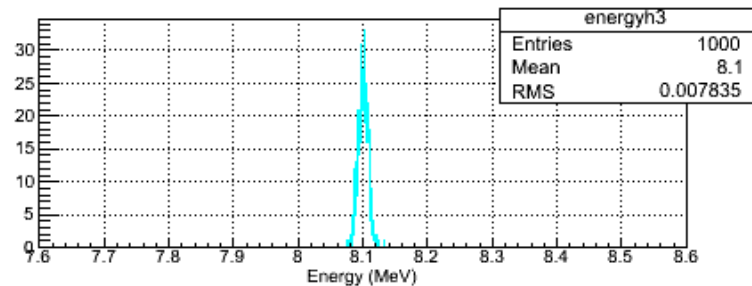
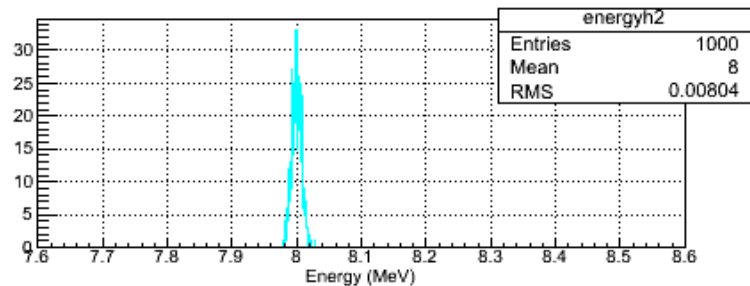
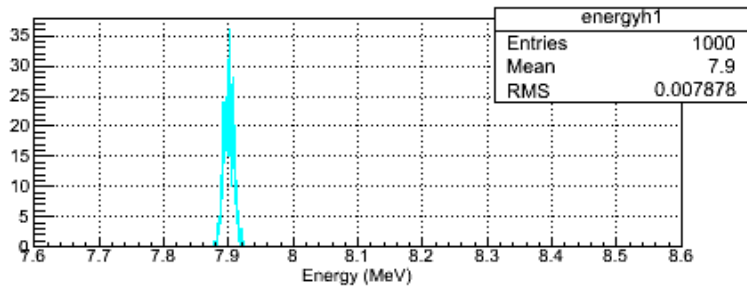
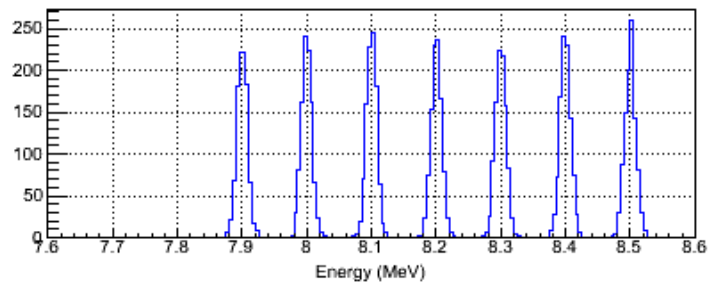
$$E_i = E_i * gRandom \rightarrow Gaus(1, 0.001)$$

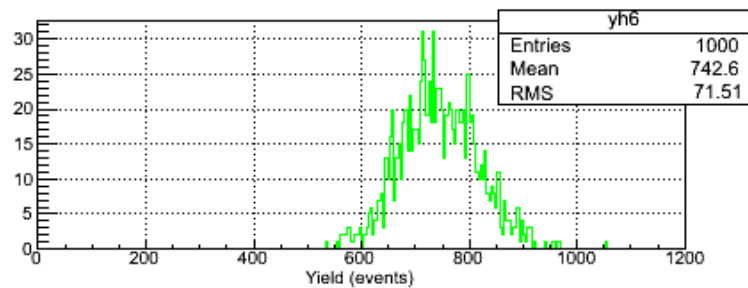
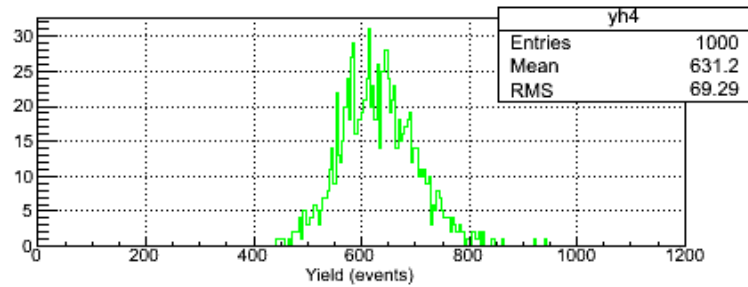
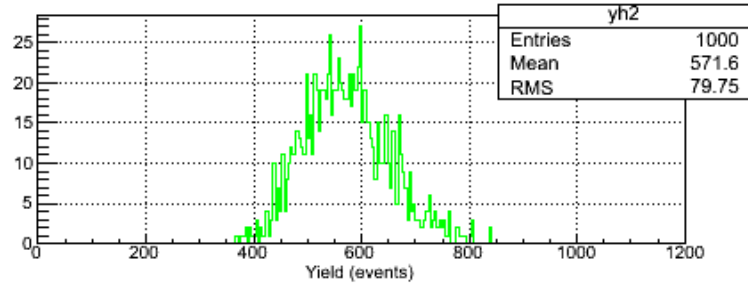
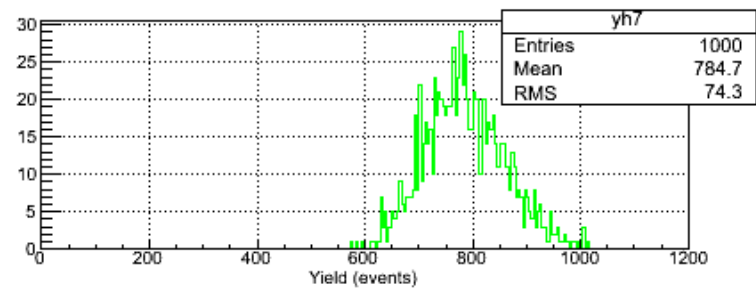
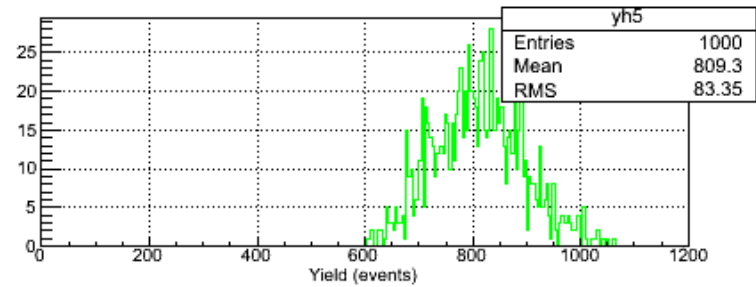
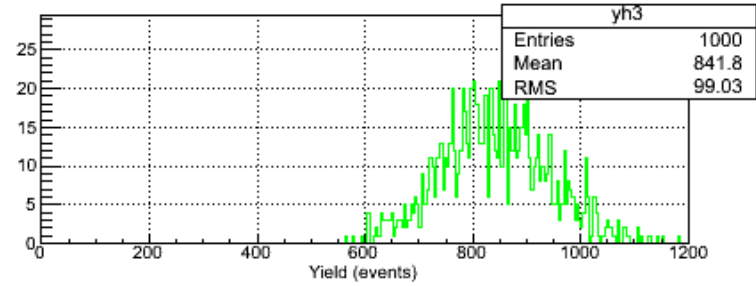
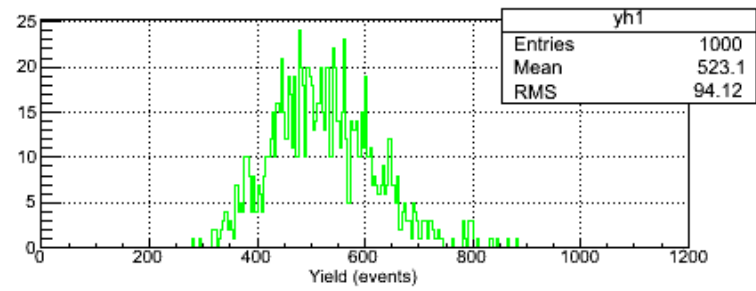
- III. Calculate the yield
- IV. Include other absolute systematic errors:

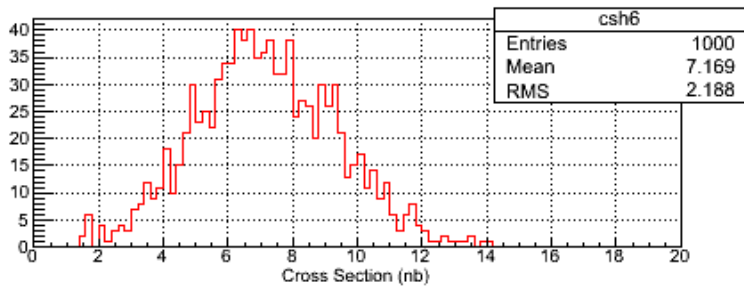
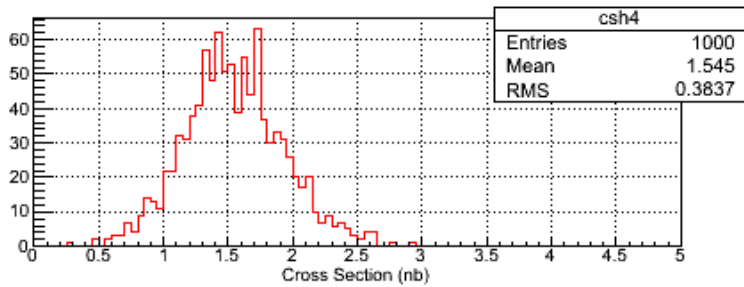
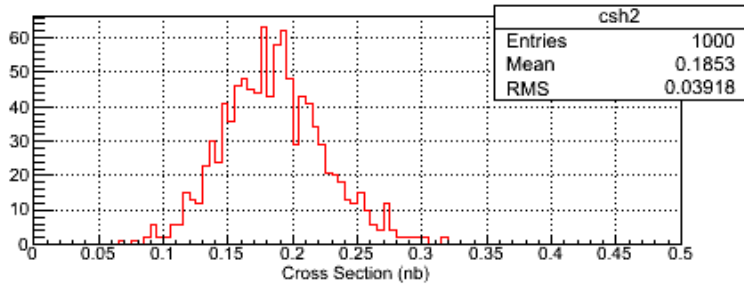
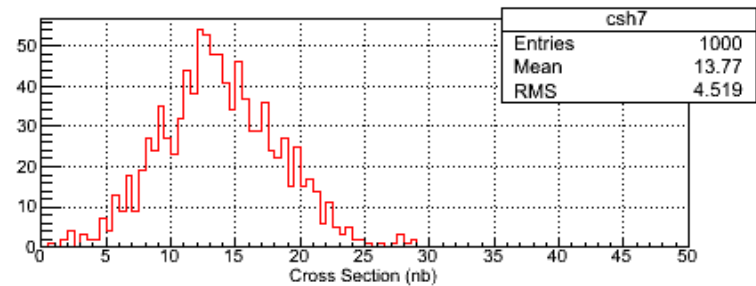
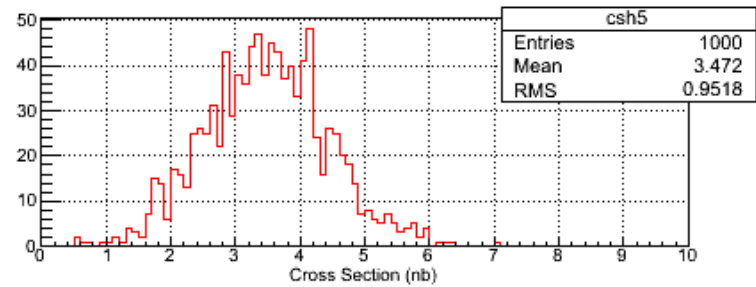
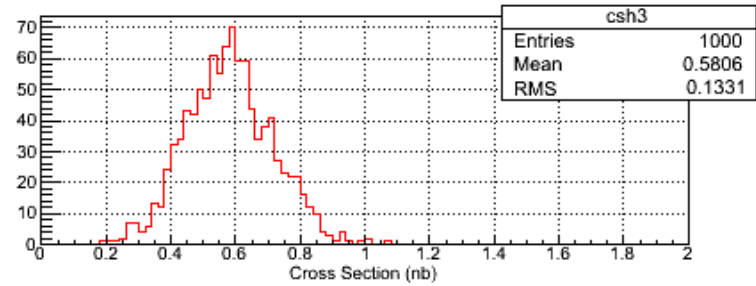
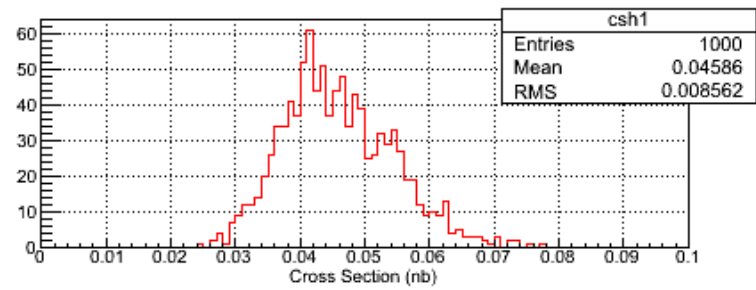
$$N_{ij} = N_{ij} * gRandom \rightarrow Gaus(1, \delta\varphi/\varphi)$$

$$y_i = y_i * gRandom \rightarrow Gaus(1, \text{Sqrt}((\delta I/I)^2 + (\delta R/R)^2 + (\delta T/T)^2 + \epsilon^2))$$

- V. Unfold cross section
- VI. Repeat for 1000 tries







Electron Beam K. E.	Beam Current (μA)	Time (hour)	y_i	dy_i/y_i (%)
7.9	100	100	523	18.0
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Electron Beam K. E.	Cross Section (nb)	Sys Error (Total, %)
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8.1	0.58	22.9
8.2	1.54	24.8
8.3	3.48	27.4
8.4	7.2	30.5
8.5	13.8	32.8

Relative Systematic Errors

Relative Beam Energy

- I. Calculate the N_{ij} for each nominal beam energy, E_i (since we will use GEANT4)
- II. Allow for absolute beam energy 7.8 MeV to change by:

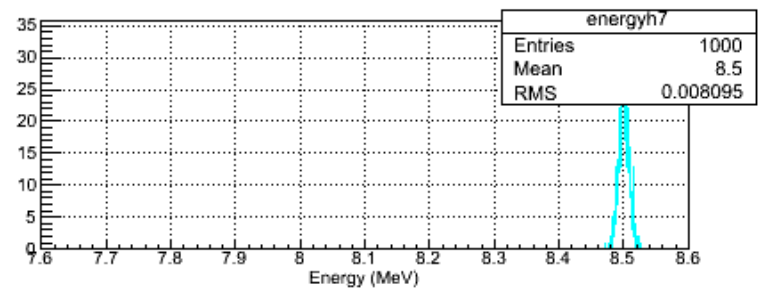
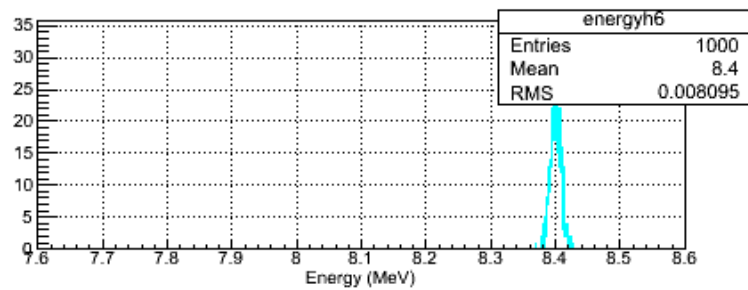
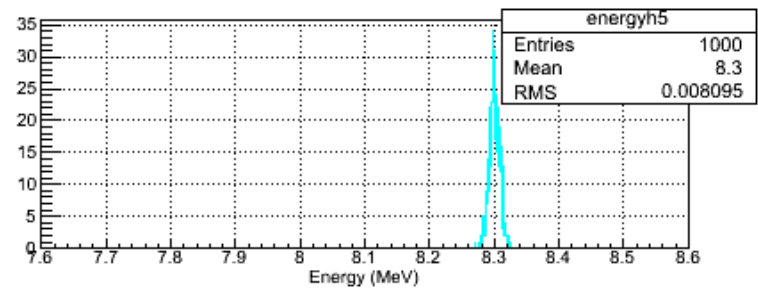
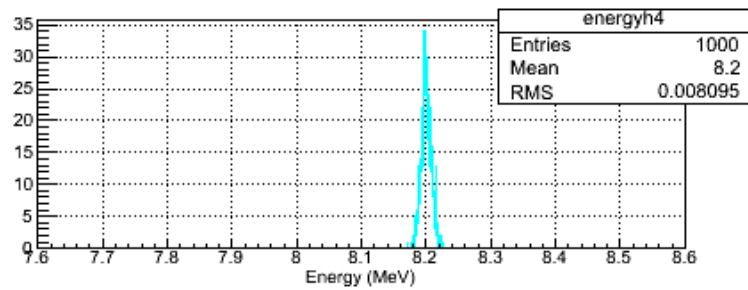
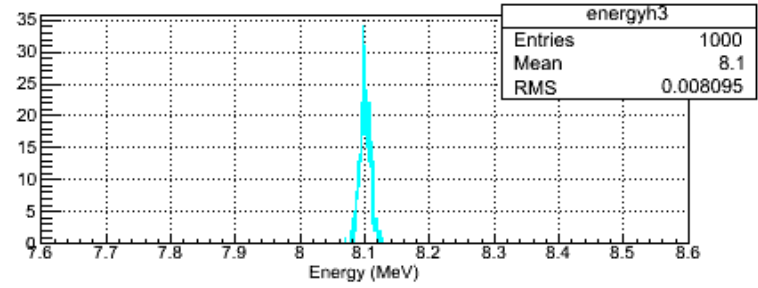
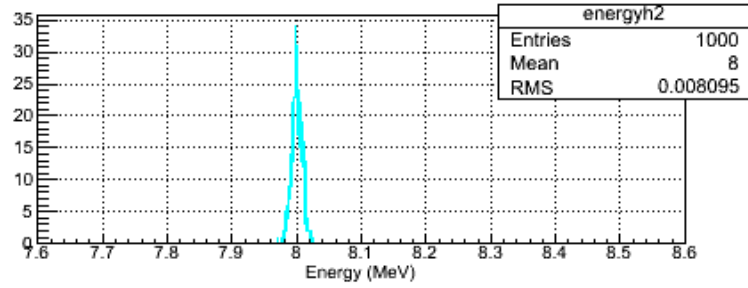
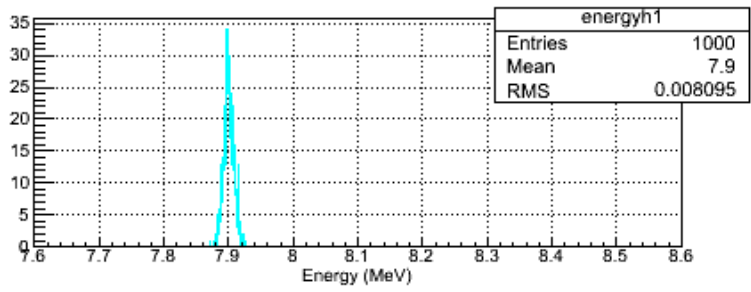
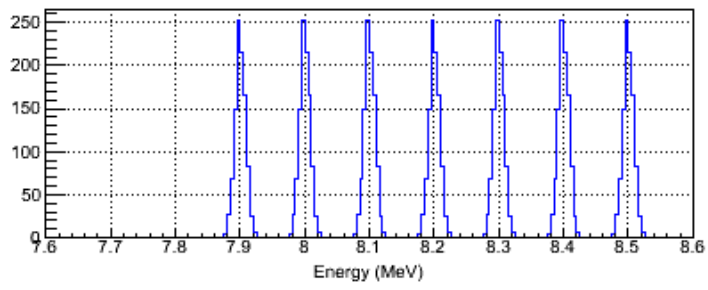
$$E_0 = 7.8 * gRandom \rightarrow Gaus(1, 0.001)$$

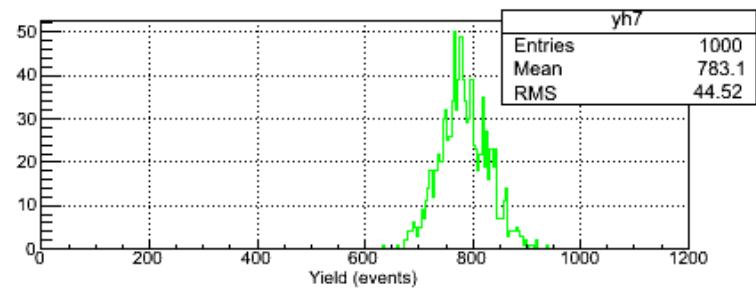
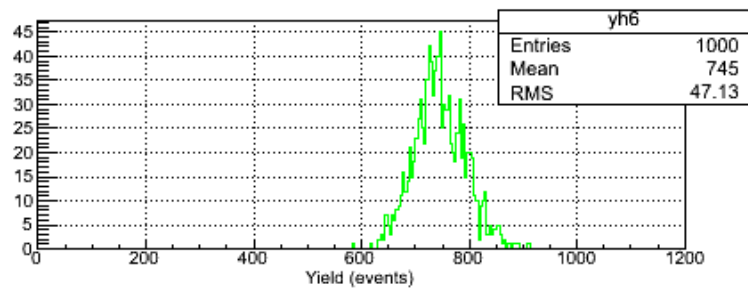
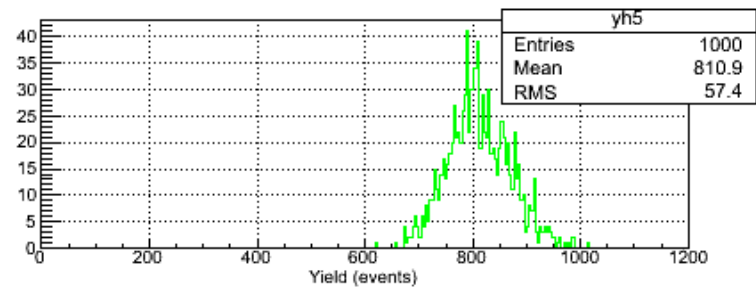
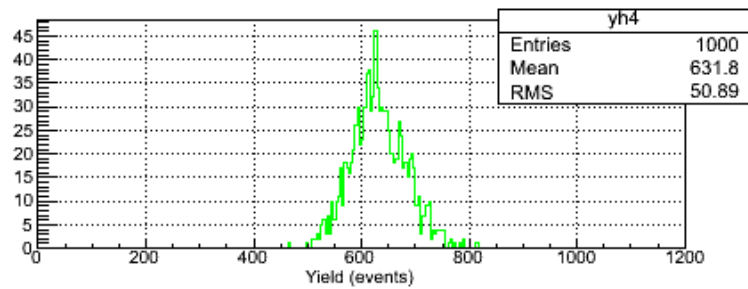
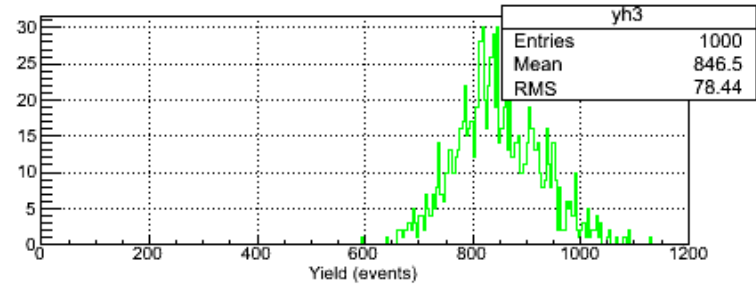
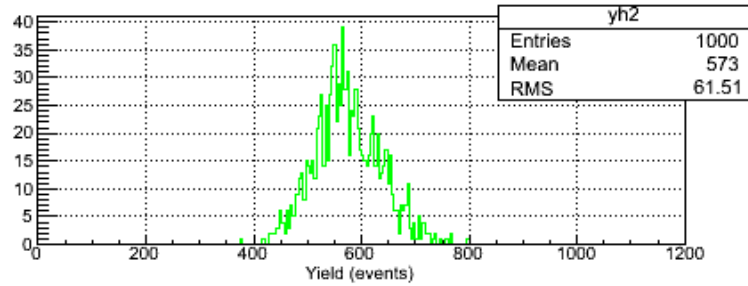
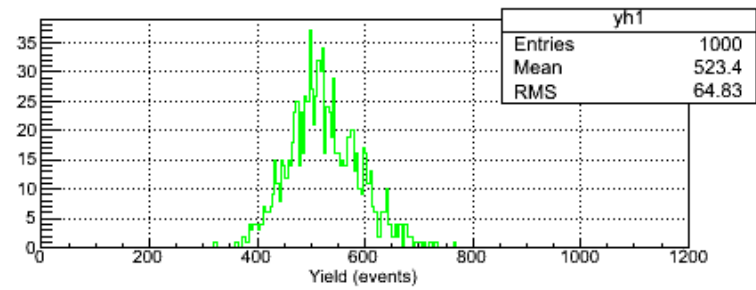
- III. Higher energies has same relative error,

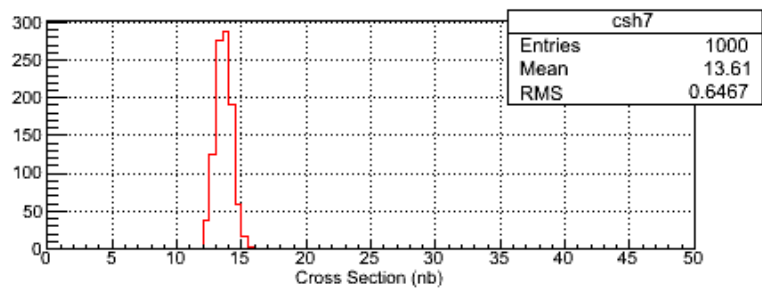
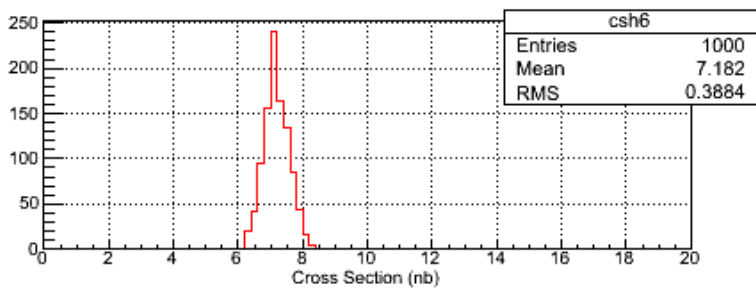
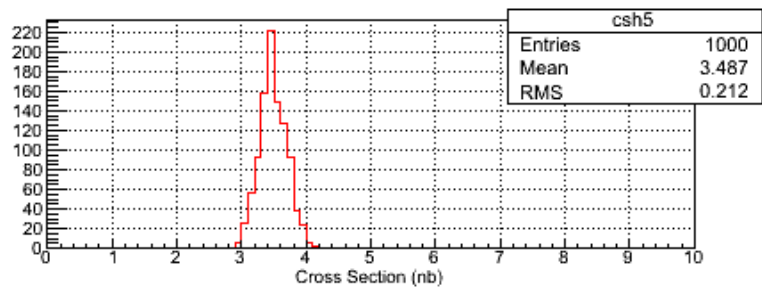
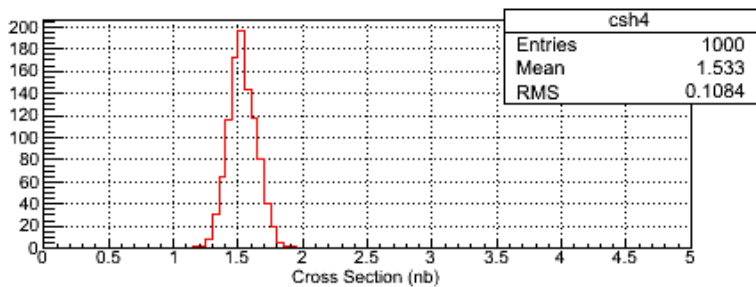
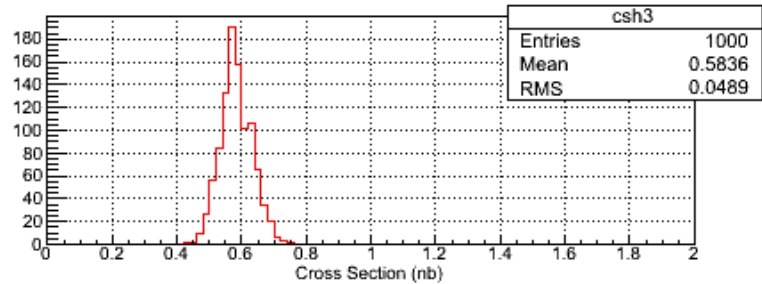
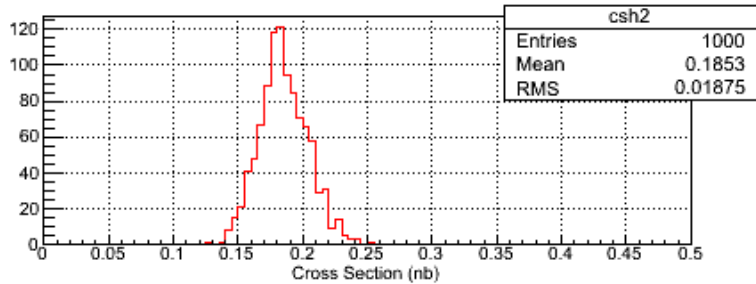
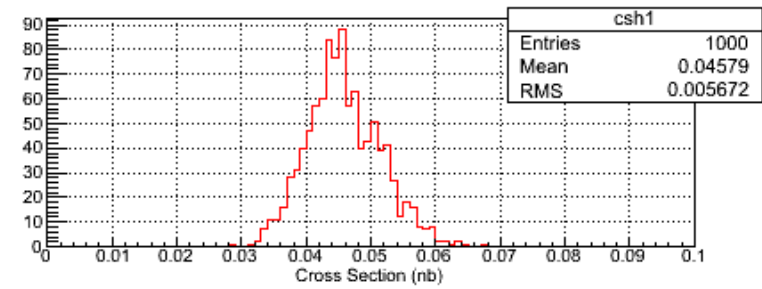
$$E_i = E_0 + i\Delta$$

- IV. Calculate the yield
- V. Unfold cross section
- VI. Repeat for 1000 tries

Now, we have to worry about beam stability (RF stability). Need injector FFB system to maintain relative beam stability





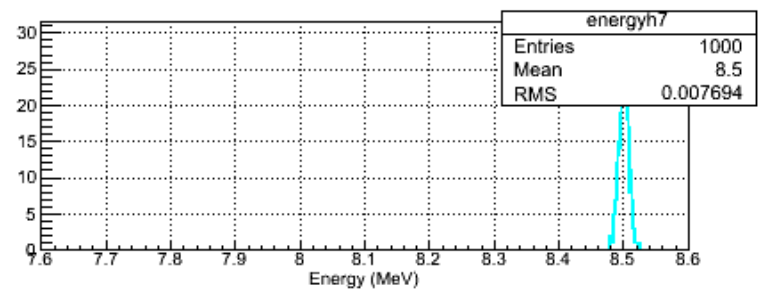
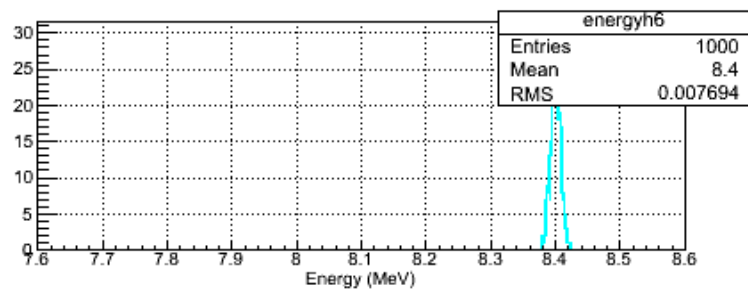
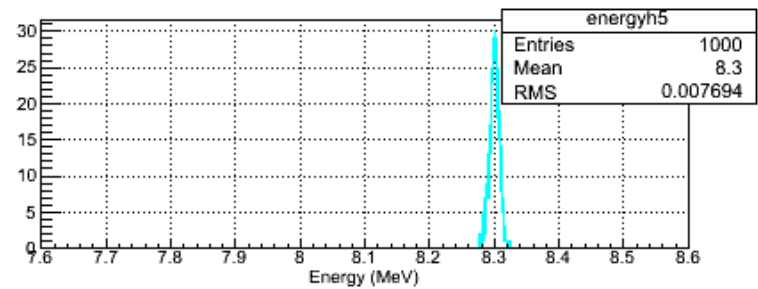
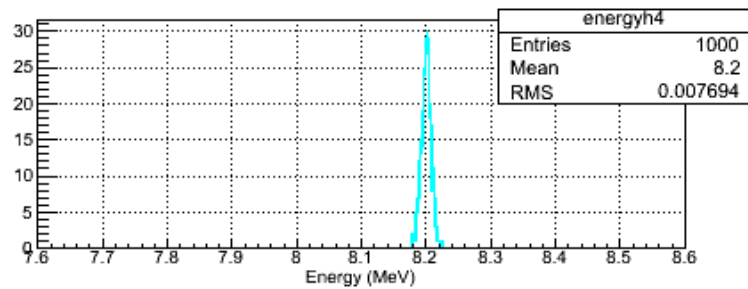
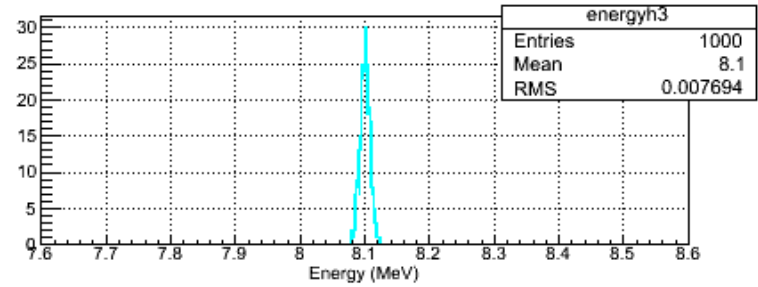
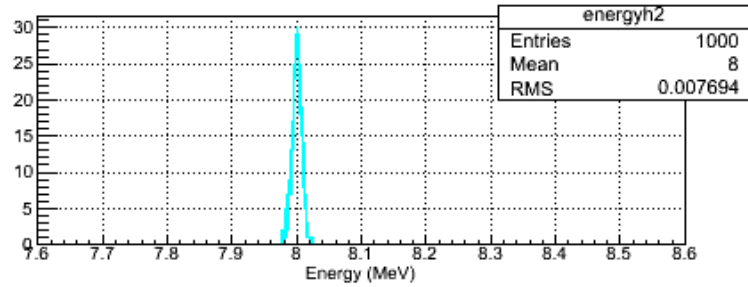
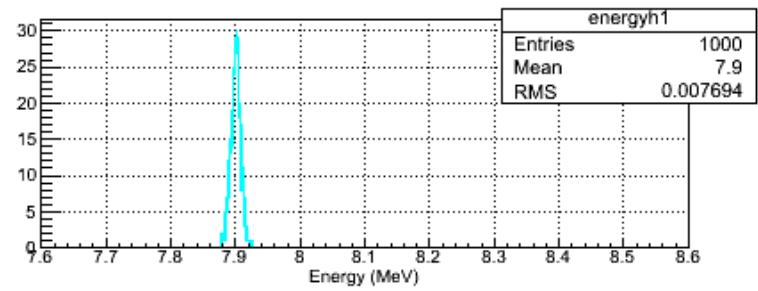
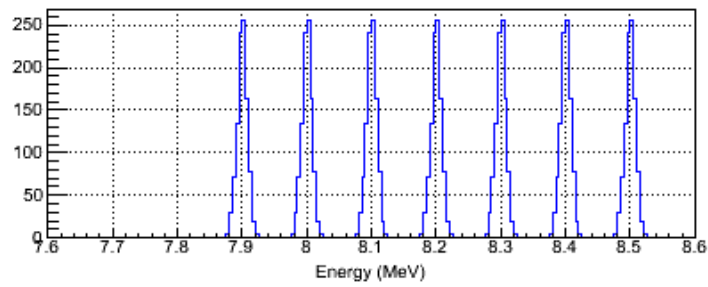


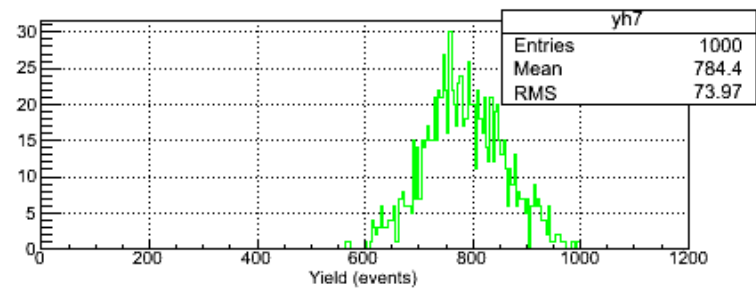
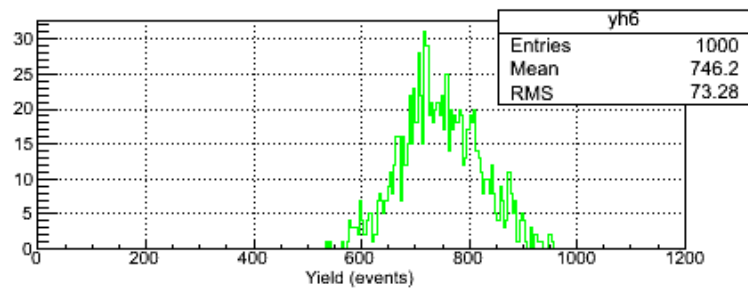
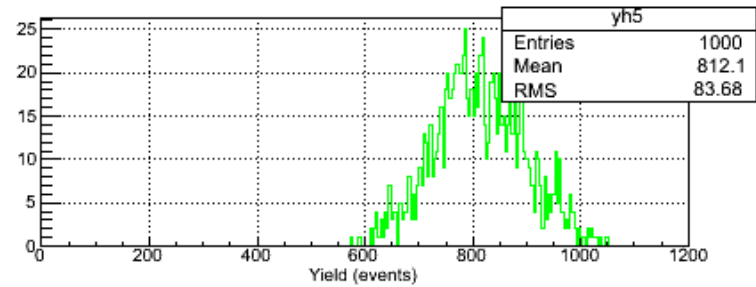
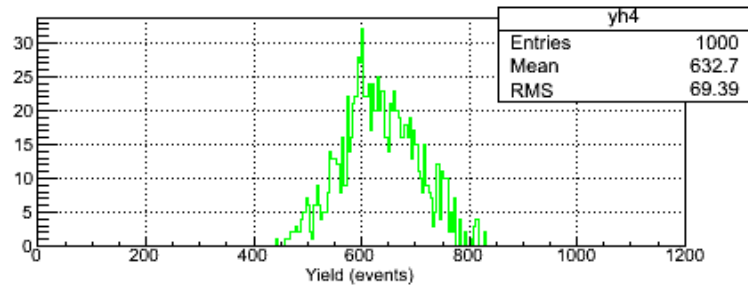
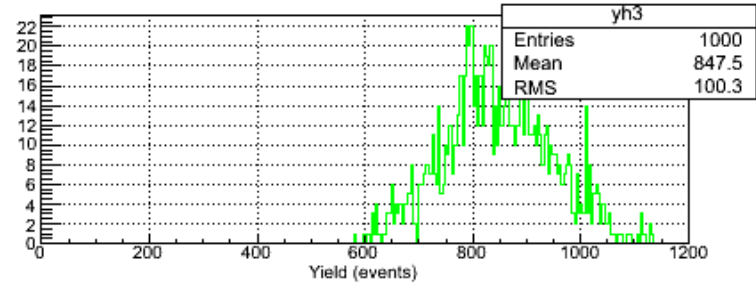
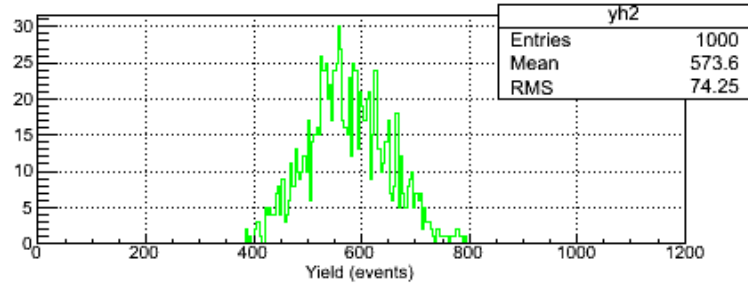
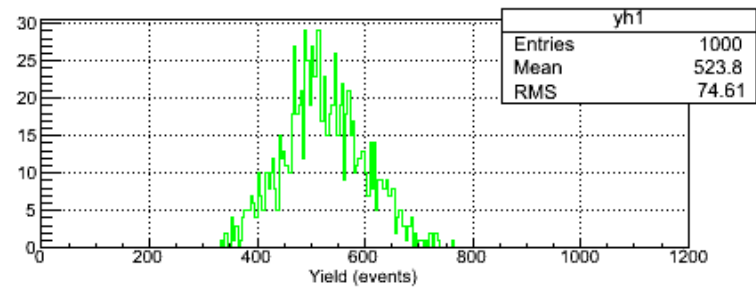
Electron Beam K. E.	Beam Current (μA)	Time (hour)	y_i	dy_i/y_i (%)
7.9	100	100	523	12.4
8.0	100	20	573	10.7
8.1	80	10	846	9.3
8.2	20	10	632	8.1
8.3	10	10	811	7.1
8.4	4	10	745	6.3
8.5	2	10	783	5.7

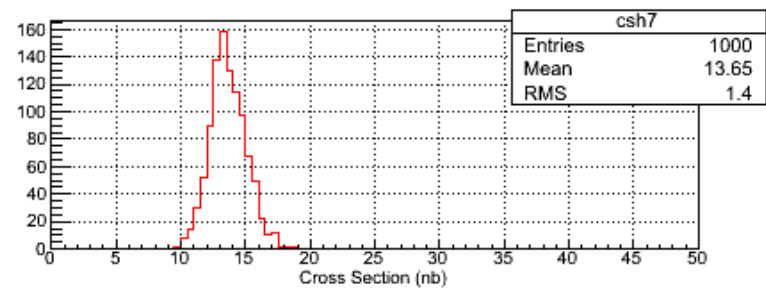
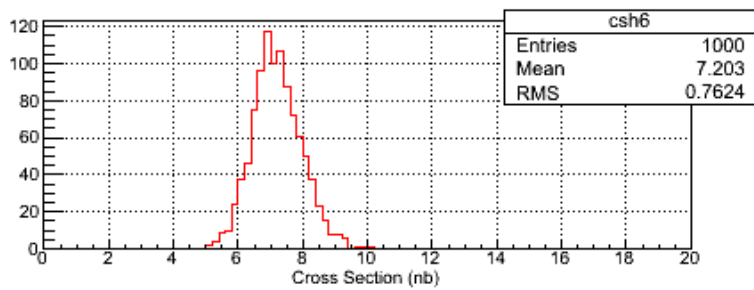
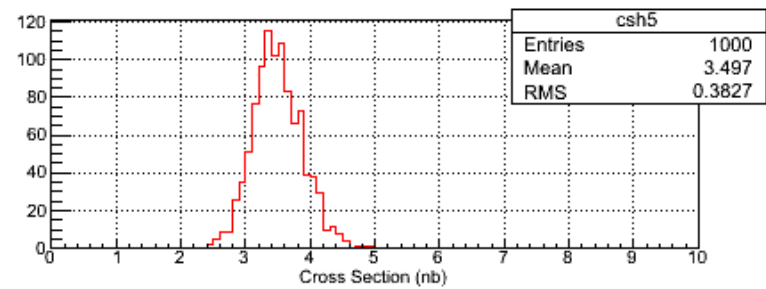
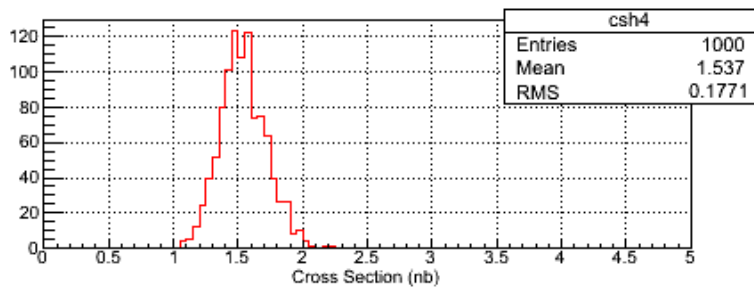
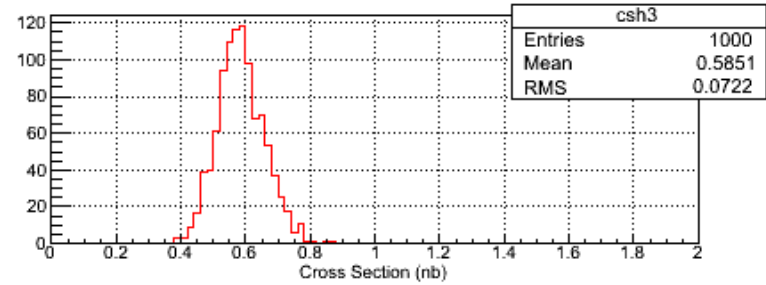
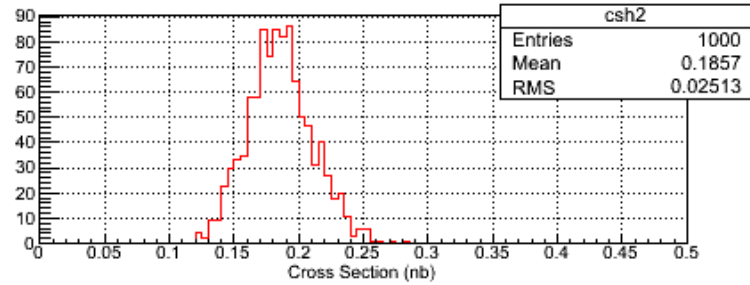
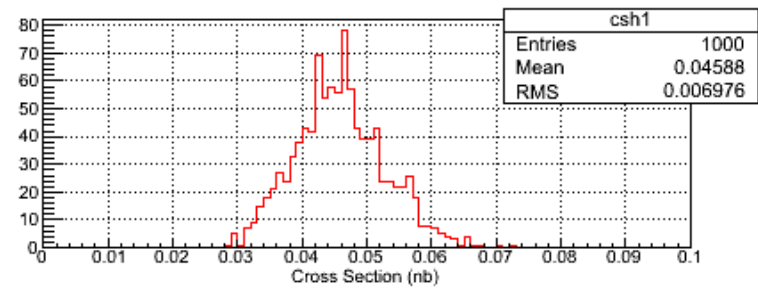
Electron Beam K. E.	Cross Section (nb)	Sys Error (Energy, %)
7.9	0.046	12.4
8.0	0.185	10.1
8.1	0.58	8.4
8.2	1.53	7.1
8.3	3.49	6.1
8.4	7.2	5.4
8.5	13.6	4.8

Other Relative Systematic Errors

- I. Calculate the N_{ij} for each nominal beam energy, E_i (since we will use GEANT4)
- II. Allow for absolute beam energy 7.8 MeV to change by: $E_0 = 7.8 * gRandom \rightarrow Gaus(1, 0.001)$
- III. Higher energies has same relative error, $E_i = E_0 + i\Delta$
- IV. Calculate the yield
- V. Include other relative systematic errors:
$$N = N * gRandom \rightarrow Gaus(1, \delta\varphi/\varphi)$$
$$y = y * gRandom \rightarrow Gaus(1, Sqrt((\delta l/l)^2 + (\delta R/R)^2 + (\delta T/T)^2 + \varepsilon^2))$$
- VI. Unfold cross section
- VII. Repeat for 1000 tries







Electron Beam K. E.	Beam Current (μA)	Time (hour)	y_i	dy_i/y_i (%)
7.9	100	100	524	14.2
8.0	100	20	574	12.9
8.1	80	10	848	11.8
8.2	20	10	633	11.0
8.3	10	10	812	10.3
8.4	4	10	746	9.8
8.5	2	10	784	9.4

Electron Beam K. E.	Cross Section (nb)	Sys Error (Total, %)
7.9	0.046	15.2
8.0	0.186	13.5
8.1	0.59	12.3
8.2	1.54	11.5
8.3	3.50	10.9
8.4	7.2	10.6
8.5	13.6	10.3